

# Infrared Reflectance Standards Survey

**INSTRUCTIONS:**

"PRIORITY" pick a priority level from the drop down menu:

- 1 = high (a critical parameter; SRM of no value without it)
- 2 = medium (important for calibration purposes, but not absolutely essential)
- 3 = low (useful, but icing on the cake)
- 0 = zero (not important, immaterial)
- 4 = none (don't know or no opinion)

**PARAMETER                      PRIORITY                      VALUES**

**Angle dependent Reflection Standards**

1	Wavelength ( $\lambda$ ) Range, ( $\mu\text{m}$ )	<input type="text"/>	2-14	3-5	8-12	10.6	<input type="text"/> - <input type="text"/>
2	Reflectance Factor (R), 1.00 = 100%	<input type="text"/>	> 0.9	0.2 - 0.7	< 0.1	< 0.02	<input type="text"/>
3	Spectral Characteristic (neutrality)	<input type="text"/>	neutral <input type="text"/>	w/ structure <input type="text"/>	<input type="text"/> <input type="text"/>		
4	Angle Range(s), $^{\circ}$	<input type="text"/>	near normal only <input type="text"/>	lower limit <input type="text"/>	upper limit <input type="text"/>	stepsize (interval) <input type="text"/>	
5	Expanded Uncertainty (k=2), %	<input type="text"/>	$\pm 10$	$\pm 5$	$\pm 2$	$\pm 1$	< $\pm 1$ <input type="text"/> <input type="text"/>
6	Standards / Calibration service	<input type="text"/>	Standards for purchase <input type="text"/>		Calibration Service at NIST <input type="text"/>		
7	Spatial Uniformity Requirement	<input type="text"/>	$\pm$ <input type="text"/> % over 90% of surface				<input type="text"/> <input type="text"/>
8	Sample Size (mm)/Geometry	<input type="text"/>	25	50	100	round	square <input type="text"/> <input type="text"/>
9	Spot Size	<input type="text"/>	<input type="text"/> mm				

10 Please indicate your instrumental application for use of a SRM:

BRDF <input type="text"/>	Integrating Sphere <input type="text"/>	Hemi-ellipsoid <input type="text"/>	Bi-Conical Designs <input type="text"/>	<input type="text"/> <input type="text"/>	<input type="text"/> <input type="text"/>
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11 Please indicate what type of instruments are used for a SRM:

FT <input type="text"/>	Monochromator <input type="text"/>	Filters <input type="text"/>	Circular Variable Filter (CVF) <input type="text"/>	<input type="text"/> <input type="text"/>
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## Measurement Intercomparison, Round-Robin

12 Your participation    other

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13 Time scale: Next comparison should be within  3 yr. 2 yr. 1 yr. 6 month

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## EO-IR Workshop (or similar)

14 Usefulness/Attendance   attended in the past  plan to attend in future

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15 Structure of the workshop  discussion groups  presentations  tutorials   
mixture of above

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16 Location  independent  part of or parallel to Conference

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17 Timing  Spring Summer Fall Winter

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## Comments

## Contact Information:

**NOTE:**

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